



## Product Change Notification - LIAL-19IVLH492

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**Date:**

30 Sep 2019

**Product Category:**

32-bit Microcontrollers

**Affected CPNs:****Notification subject:**

CCB 3655 Final Notice: Qualification of MMT as an additional assembly site for selected Atmel products of 58.85K and 58.8K wafer technologies available in 48L VQFN (7x7x0.9mm) package.

**Notification text:****PCN Status:**

Final notification

**PCN Type:**

Manufacturing Change

**Microchip Parts Affected:**

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:**

Qualification of MMT as an additional assembly site for selected Atmel products of 58.85K and 58.8K wafer technologies available in 48L VQFN (7x7x0.9mm) package.

**Pre Change:**

Assembled at ASE using EN-4900F die attach material.

**Post Change:**

Assembled at ASE using EN-4900F die attach material or assembled at MMT using 3280 die attach material

**Pre and Post Change Summary:**

	Pre Change	Post Change	
<b>Assembly Site</b>	ASE Inc. (ASE)	ASE Inc. (ASE)	Microchip Technology Thailand  (Branch) (MMT)
<b>Wire material</b>	Au	Au	Au
<b>Die attach material</b>	EN-4900F	EN-4900F	3280
<b>Molding compound material</b>	G700	G700	G700
<b>Lead frame material</b>	C194	C194	C194



MSL level	MSL 3	MSL 3	MSL 1
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**Impacts to Data Sheet:**

Yes. POD (package outline drawing) change. See the changes below:

Dimension Limit (in mm)	Pre Change			Post Change		
	Min	Nor	Max	Min	Nor	Max
Number of terminals	48			48		
Overall Height	0.8	0.85	0.9	0.8	0.9	1
Standoff	0	0.02	0.05	0	-	0.05
Terminal Thickness	0.20 REF			0.20 REF		
Overall Length	7.00 BSC			7.00 BSC		
Exposed Pad Length	5.5	5.6	5.7	5.5	5.6	5.7
Overall Width	7.00 BSC			7.00 BSC		
Exposed Pad Width	5.5	5.6	5.7	5.5	5.6	5.7
Terminal Width	0.17	0.25	0.3	0.2	0.25	0.3
Terminal Length	0.3	0.4	0.5	0.3	0.4	0.5
Pitch	0.50 BCS			0.50 BCS		

**Note:** These POD changes are within JEDEC limit so no significant impact other than a documentation change in the spec and/or datasheet.

**Change Impact**

None

**Reason for Change:**

To improve productivity and on-time delivery performance by qualifying ASE as an additional assembly site.

**Change Implementation Status:**

In Progress

**Estimated First Ship Date:**

October 30, 2019 (date code: 1944)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts

**Time Table Summary:**

Workweek	December 2018				-->	September 2019					October 2019			
	49	50	51	52		36	37	38	39	40	41	42	43	44
Initial PCN Issue Date				X										
Qual Report Availability										X				
Final PCN Issue Date										X				
Estimated Implementation Date														X

**Method to Identify Change:**

Traceability code

**Qualification Report:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report.

**Revision History:**

**December 27, 2018:** Issued initial notification.

**September 30, 2019:** Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on October 30, 2019.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):**

[PCN\\_LIAL-19IVLH492\\_QUAL\\_REPORT.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

**Terms and Conditions:**

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If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

AT91SAM7S32B-MU  
AT91SAM7S32B-MU-999  
ATSAM3N00AA-MU  
ATSAM3N00AA-MUR  
ATSAM3N0AA-MU  
ATSAM3N0AA-MUR  
ATSAM3N1AB-MU  
ATSAM3N1AB-MUR  
ATSAM3S1AB-MU  
ATSAM3S1AB-MUR  
ATSAM3S2AA-MU  
ATSAM3S2AA-MUR  
ATSAM3S4AA-MU  
ATSAM3S4AA-MUR



**MICROCHIP**

**QUALIFICATION REPORT SUMMARY**  
RELIABILITY LABORATORY

**PCN #: LIAL-19IVLH492**

**Date**

**September 13, 2019**

**Qualification of MMT as an additional assembly site for  
selected Atmel products of 58.85K and 58.8K wafer  
technologies available in 48L VQFN (7x7x0.9mm)  
package.**



# MICROCHIP

## Package Qualification Report

**Purpose:** Qualification of MMT as an additional assembly site for selected Atmel products of 58.85K and 58.8K wafer technologies available in 48L VQFN (7x7x0.9mm) package.

<b><u>Miscellaneous</u></b>	Assembly site	MMT
	BD Number	BDM-001983/A
	MP Code (MPC)	58Z25TSMBC02
	Part Number (CPN)	ATSAM3S2AA-MUR
	CCB No.	3655
	Quad id and rev	QTP3774 Rev A
<b><u>Lead-Frame</u></b>	Paddle size	228x228 mils
	Material	C194
	DAP Surface Prep	Selective Ag
	Treatment	BOT
	Process	Etched
	Lead-lock	No
	Part Number	10104810
	Lead Plating	Matte tin
	Strip Size	70x250
Strip Density	240	
<b><u>Bond Wire</u></b>	Material	Au
<b><u>Die Attach</u></b>	Part Number	3280
	Conductive	Yes
<b><u>Mold Compound</u></b>	Part Number	G700LTD
<b><u>PKG</u></b>	PKG Type	VQFN
	Pin/Ball Count	48L
	PKG width/size	7x7x0.9mm
<b><u>Die</u></b>	Die Thickness	11 mils
	Die Size	176.65x166.18 mils
	Fab Process (site)	UMC/58.85K
	MSL	MSL-1@260C



# MICROCHIP Package Qualification Report

## Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
194501806000MMT	U8CD919280632.200#15	1906252
194501807000MMT	U8CD919280632.200#16	190724W
194600347000MMT	U8CD919280632.200#15	1907251

**Result**

Pass

Fail

Atmel MCT32 "58Z25" Ground bonding products on 48L VQFN 7x7 (SMB) Au at MMT pass reliability test per microchip qualification rules. This package was qualified the Moisture/ Reflow Sensitivity Classification Level 1 at 260°C reflow temperature. Reliability assessment has been made as authorized by QCI-39000-002 and J-STD-020E standards.

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)</b>	85°C/85%RH Moisture Soak 168 hrs. System: Climats Excal 5423-HE 3x Convection-Reflow 265°C max System: Mancorp CR.5000F  (IPC/JEDEC J-STD-020E)	JEDEC J-STD-020E	45 units per lot	Lot 1 0/45	Pass	
				Lot 2 0/45	Pass	
				Lot 3 0/45	Pass	
<b>Precondition Prior Perform Reliability Tests (At MSL Level 1)</b>	<b>Electrical Test :25°C</b> Done in ASE  Bake 150°C, 24 hrs System: HERAEUS  85°C/85%RH Moisture Soak 168 hrs. System: Climats Excal 5423-HE  3x Convection-Reflow 265°C max System: Mancorp CR.5000F  <b>Electrical Test : 25C</b> Done in ASE	JESD22-A113  JEDEC J-STD-020E	231 units per lot	Lot 1 0/231	Pass	Good Devices
				Lot 2 0/231	Pass	
				Lot 3 0/231	Pass	



# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>UNBIASED HAST</b>	<b>Stress Condition:</b> (Standard) + 130°C, 85%RH, 96 hrs. System: HIRAYAMA HASTEST PC-422R8  <b>Electrical Test:</b> 25°C Done in ASE	JESD22-A118	77 units per lot	Lot 1 0/77	Pass	Parts had been pre-conditioned at 260°C
				Lot 2 0/77	Pass	
				Lot 3 0/77	Pass	
<b>HAST</b>	<b>Stress Condition:</b> (Standard) +130°C, 85%RH, 96 hrs. VOLTS=5.5V System: HIRAYAMA HASTEST PC-422R8  <b>Electrical Test:</b> 25°C Done in ASE	JESD22-A110	77 units per lot	Lot 1 0/77	Pass	Parts had been pre-conditioned at 260°C
				Lot 2 0/77		
				Lot 3 0/77		

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Temp Cycle</b>	<b>Stress Condition:</b> (Standard) -65°C to +150°C, 500 Cycles System: Votsch VTS <sup>2</sup> 7012  <b>Electrical Test:</b> 25°C Done in ASE	JESD22-A104	77 units per lot	Lot 1 0/77	Pass	Parts had been pre-conditioned at 260°C
	Lot 2 0/77			Pass		
Lot 3 0/77	Pass					
<b>High Temperature Storage Life</b>	<b>Bond Strength:</b> Wire Pull (> 1.75 grams) Bond Shear (>12.6 grams) System: Dage Cpk > 1.67	JESD22-A103	5 units per lot	Lot 1, 0/5	Pass	
				Lot 2, 0/5	Pass	
				Lot 3, 0/5	Pass	
<b>High Temperature Storage Life</b>	<b>Stress Condition:</b> Bake 175°C, 500 hrs System: HERAEUS  <b>Electrical Test:</b> 25°C Done in ASE	JESD22-A103	45 units per lot	Lot 1 0/45	Pass	
				Lot 2 0/45	Pass	
				Lot 3 0/45	Pass	

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>Bond Strength, 0 Hour</b>	<b>System:</b> Dage Wire Pull (> 1.75 grams) Bond <i>Shear</i> (>12.6 grams) CpK > 1.67		5 units per lot	Lot 1 0/5	Pass	
				Lot 2 0/5	Pass	
				Lot 3 0/5	Pass	
<b>PHYSICAL DIMENSIONS</b>	Physical Dimension, 30 units from 3 lots	JESD22 -B100/B108	10 units per lot	Lot 1 0/10	Pass	
				Lot 2 0/10	Pass	
				Lot 3 0/10	Pass	